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**Semiconductor Process and Yield Analysis Integrated Real-time Management
Method**

Appl. No. : 10/708,277 Confirmation No. 2276
Applicant : Hung-En Tai,
Chien-Chung Chen,
Sheng-Jen Wang
Filed : February 20, 2004
TC/A.U. : 2125
Examiner : GARLAND, STEVEN R
Docket No. : LKSP0045USA0
Customer No. : 27765

Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

AMENDMENT

5 Sir:

In response to the Office action of February 08, 2006, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of
10 this paper.

Remarks/Arguments begin on page 7 of this paper.